

QUADRUPLE 2-INPUT | S5437 N7437

POSITIVE NAND BUFFER S5438 N7438

\$5437-A,F,W • \$5438-A,F,W • \$5439-A,F • N7437-A,F,W • N7438-A,F • N7439-A,F

PIN CONFIGURATIONS

S5439 N7439

DIGITAL 54/74 TTL SERIES

DESCRIPTION

The S5437/N7437 is a NAND Gate (output low onlywhen all inputs are high) the same as N7400 except that it will drive 3 times as many loads. The S5438/N7438 and S5439/N7439 are also NAND Gates but have open-collectors similar to N7403.

The S5437/N7437, S5438/N7438 and S5439/N7439 contain four 2-input NAND gates in a package with a guaranteed fan-out of 30-series 54/74 loads in both the logical "1" (1.2mA), and logical "0" (48mA) states. The S5438/N7438 and S5439/N7439 have an open collector output for "WLRE-AND," applications but still retain the high sink current capability of the S5437/N7437.

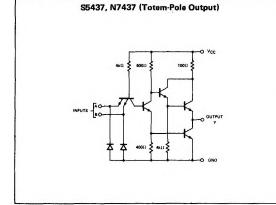
ABSOLUTE MAXIMUM RATINGS (over operating temperature ranges unless otherwise noted)

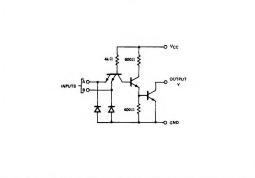
Supply Voltage V _{CC} (See Note 1)	7V
Supply Voltage (See Note 1)	5.5V
Intermitter Voltage (See Note 2)	5.5V
Output Voltage (See Notes 1 and 3): S5438/N7438, S5439/N7439	5.5V
Operating Free-Air Temperature Range: S5437/S5438/S5439 N7437/N7438/N7439 Storage Temperature Range	-55°C to 125°C 0°C to 70°C -65°C to 150°C
Storage Temperature Nange	-05 C to 150 C

NOTES:

- 1. Voltage values, except intermitter voltage, are with respect to network ground terminal.
- This is the voltage between two emitters of a multiple-emmitter transistor.
- 3. This is the maximum voltage which should be applied to any output when it is in the off state.

SCHEMATICS (each buffer)

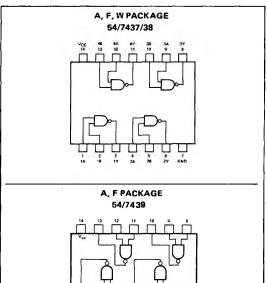




S5438, N5438, S5439, N7439 (Open-Collector Output)

RECOMMENDED OPERATING CONDITIONS

	S543	S5437, S5438, S5439			N7437, N7438, N7439			
	MIN	TYP	MAX	MIN	TYP	MAX	UNIT	
Supply Voltage V _{CC}	4.5	5	5.5	4.75	5	5.25	V	
Normalized Fan-Out from each Output, N			30			30		
Operating Free-Air Temperature Range, T _A	-55	25	125	0	25	70	°C	



ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		PARAMETER TEST CONDITIONS •		MIN	T YP **	MAX	UNIT
VIH	High-level input voltage			2			v
V _{IL}	Low-level input voltage					0.8	v
v _i	Input clamp voltage	V _{CC} = MAX,	I _I = -12mA			-1.5	v
v _{он}	High-level output voltage	V _{CC} = MIN, I _{OH} = 1.2mA	V _{IL} = 0.8V	2.4	3,3		v
V _{OL}	Low-level output voltage	V _{CC} = MIN, I _{OL} = 48mA	V _{IH} = 2V		0.22	0.4	v
4	Input current at max, input voltage	V _{CC} = MAX,	V ₁ = 5.5V			1	mA
Чн	High-level input current	V _{CC} = MAX.	V ₁ = 2.4V			40	μΑ
ΙL	Low-level input current	V _{CC} = MAX,	V ₁ = 0.4V			-1.6	mA
				-20		-55	
los -	Short-circuit output current	V _{CC} = MAX		-18		-55	mA
ссн	Supply current, high-level output	V _{CC} = MAX,	See Note 2		9	15.5	mA
CCL	Supply current, low-level output	V _{CC} = MAX,	See Note 3		34	54	mA

SWITCHING CHARACTERISTICS, V_{CC} = 5V, T_A = 25°C, N = 10

	PARAMETER 54/7437	TEST CONDITIONS	MIN TY	P MAX	UNIT
Propagation delay time, ^t PHL high-to-low-level output	C = 4505 B = 1220	1	3 22	ns	
^t PLH	Propagation delay time, PLH low-to-high-level output	C _L = 45pF, R _L = 133Ω		B 15	ns

* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

•• All typical values are at $V_{CC} = 5V$, $T_A \approx 25^{\circ}C$. † Not more than one output should be shorted at a time.

	PARAMETER 64/7438/39	TEST CONDITIONS	MIN	ТҮР	MAX	
^t PHL	Propagation delay time, high-to-low-level output			14	22	ns
touri	Propagation delay time,	$C_{L} = 45 pF, R_{L} = 133 \Omega$				
^t PLH	low-to-high-level output			11	18	ns